



PHASICS
The phase control company

SID4-eSWIR

HIGH RESOLUTION EXTENDED SWIR WAVEFRONT SENSOR

The SID4-eSWIR wavefront sensor integrates PHASICS patented technology with a T2SL detector. Thanks to its high spatial resolution and great sensitivity, it offers accurate wavefront measurement over the extended SWIR range from 0.9 to 2.35 μm .

SID4-eSWIR is an innovative solution for testing SWIR sources and lenses used in optical communications, inspection instruments or night vision in military and surveillance devices. It provides both MTF and aberrations in one single shot.

APPLICATIONS: [Free-Space Optical Communication](#) | [Defense & Security](#) | [Aerospace](#)

SPECIFICATIONS

Wavelength range	0.9 - 2.35 μm
Aperture dimensions	9.60 x 7.68 mm ²
Phase spatial resolution	120 μm
Phase & Intensity sampling	80 x 64
Resolution (Phase)	< 6 nm RMS*
Accuracy	< 40 nm RMS*
Real-time processing frequency	> 10 Hz (full resolution)
Interface	USB 2.0
Dimensions	90 x 115 x 120 mm ³
Weight	~ 1.8 kg

* For coherent sources



光技術をサポートする
株式会社オプトサイエンス

<https://www.optoscience.com>

東京本社 〒160-0014 東京都新宿区内藤町1番地 内藤町ビルディング TEL:03-3356-1064
大阪営業所 〒532-0011 大阪市淀川区西中島7-7-2 新大阪ビル西館 TEL:06-6305-2064
名古屋営業所 〒450-0002 名古屋市中村区名駅2-37-21 東海ソフトビル TEL:052-569-6064

E-mail : info@optoscience.com